

SXNS17

Monday, July 15, 2024

Instrumentation and methods I: Instrumentation and methods I (4:20 PM - 6:10 PM)

-Conveners: Tom Arnold

time	[id] title	presenter
4:20 PM	[09] Reinventing lost art in reflectometry – as illustrated by polymer brushes	Dr NELSON, Andrew
4:50 PM	[18] ML-based online analysis and autonomous closed-loop experiments at synchrotron beamlines: A case study in x-ray reflectometry	STAROSTIN, Vladimir
5:10 PM	[31] The ESTIA beamline at ESS - a new paradigm for neutron reflectometry	COOPER, Joshaniel
5:30 PM	[68] Local atomic structure of highly ordered and highly disordered thin films: recent advances of in situ grazing incidence total x-ray scattering	DIPPEL, Ann-Christin Mr GUTOWSKI, Olof Dr ZIMMERMANN, Martin v.
5:50 PM	[0] Development of neutron reflectometry tomography and its application to polymer interfaces	AOKI, Hiroyuki